

Electronic Supplementary Information (ESI) available:

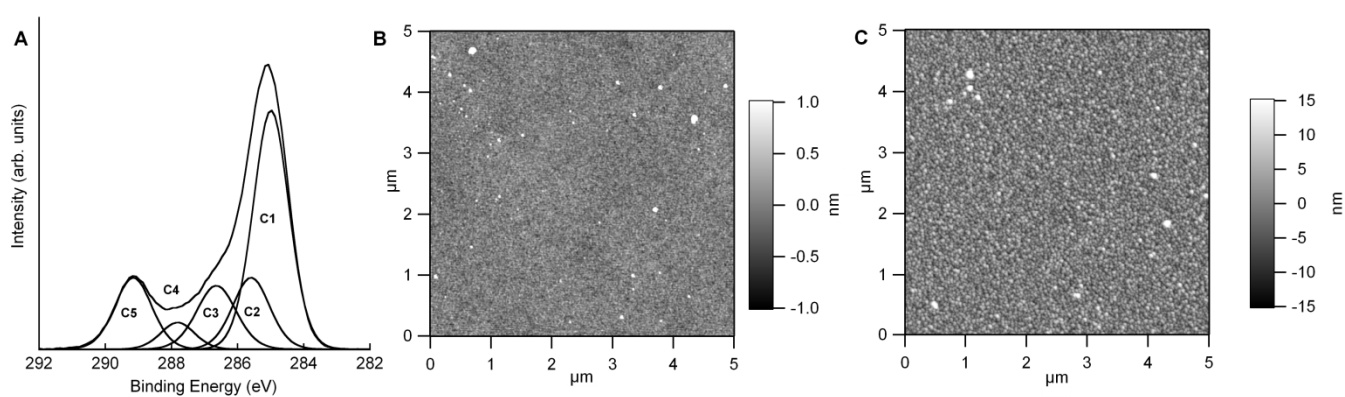


Fig. S1. Selected, representative data of ppAAc on Si wafer, (A) XPS high res C 1s, (B) AFM, (C) AFM of PEI on ppAAc on Si wafer.

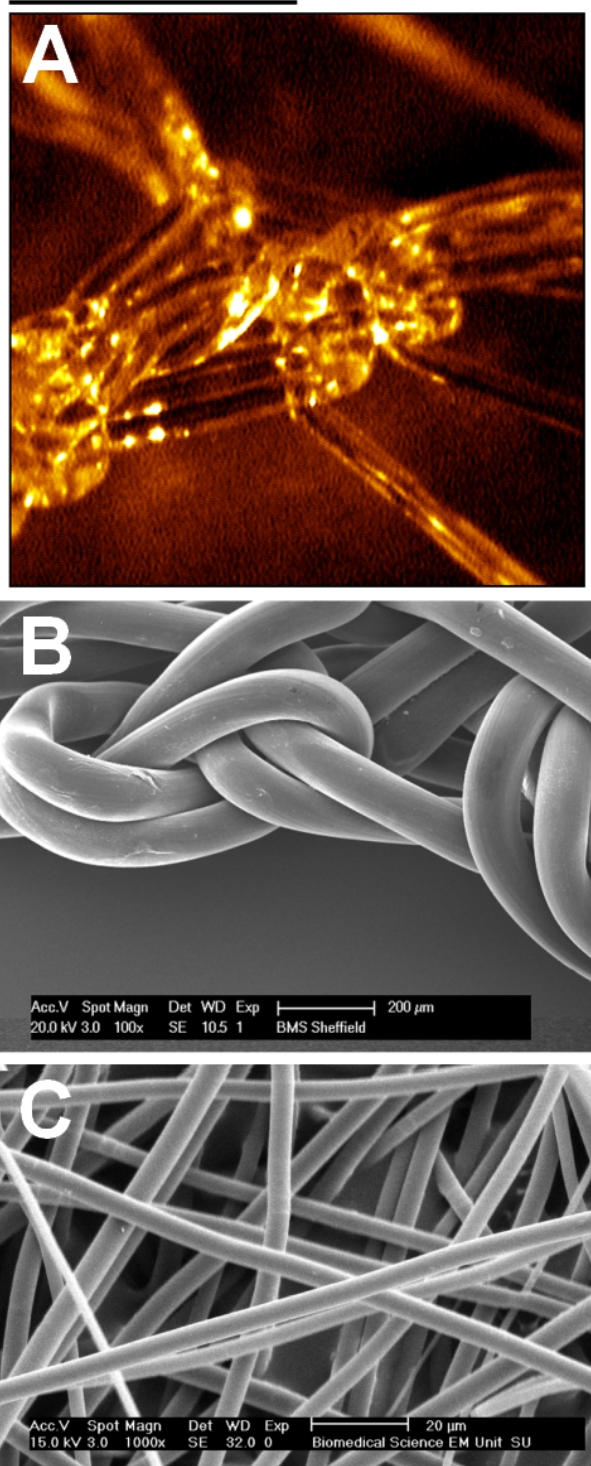


Fig. S2. (A) Optical image of PP scaffold (example of position used for XPS analysis, scale bar = 500 μm), SEM photographs of (B) PP scaffold, 100x magnification and (C) electrospun PLGA scaffold, 1000x magnification.

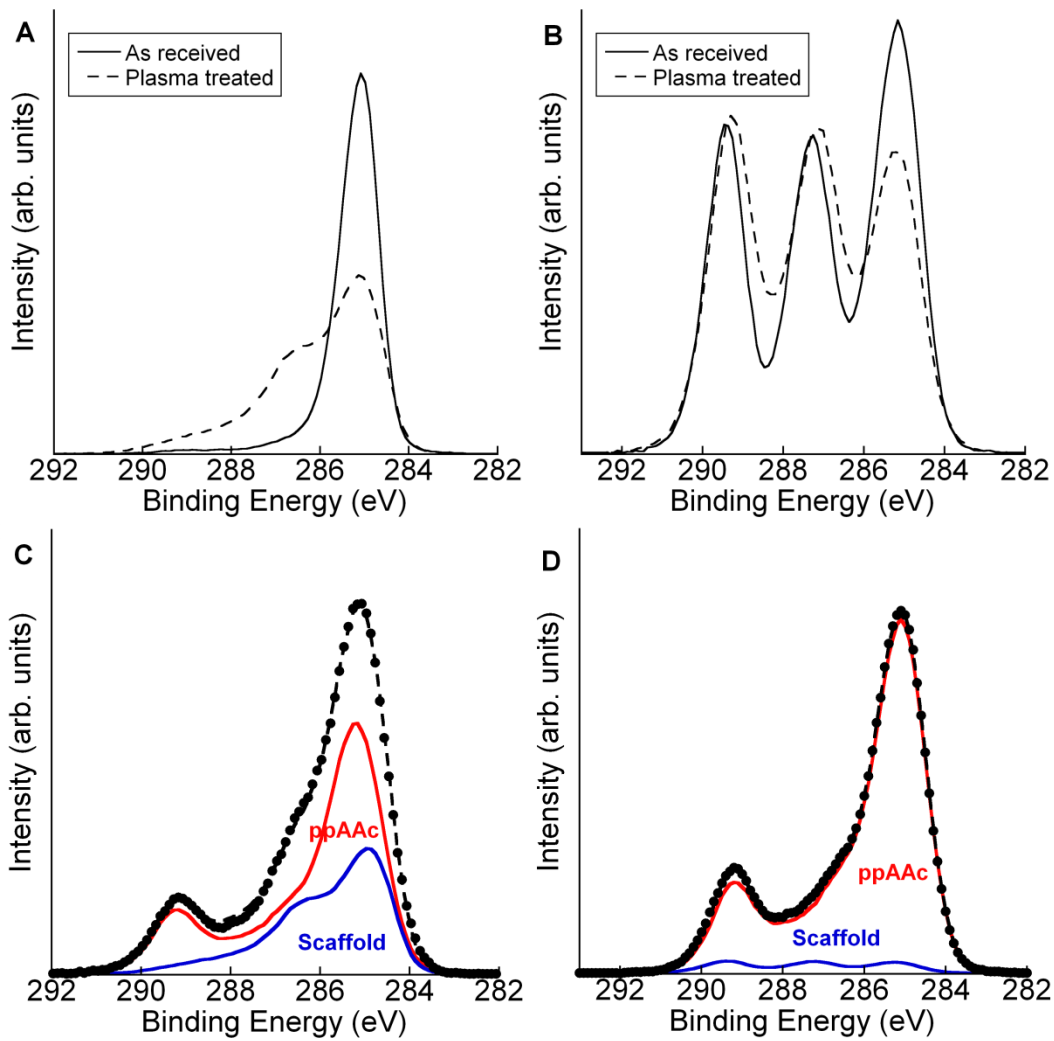


Fig. S3. Selected, representative XPS high resolution C 1s spectra of samples prepared on tissue scaffolds (A) PP as received and plasma treated, (B) PLGA as received and plasma treated, (C) PP + plasma treatment + ppAAc, (D) PLGA + plasma treatment + ppAAc